

Some pC systematics

polar. mtg.
21.01.15

Principle:

- Two independent measurements same quantity,
e.g. $X1$ & $X2$, with stat. uncert. σ_{X1} , σ_{X2}
- Distribution of trials: $(X1-X2)/(\sigma_{X1} \oplus \sigma_{X2})$
- Width of distribution: $\approx 1 \Rightarrow$ stat. uncert. accounts for deviations
 $> 1 \Rightarrow$ additional systematic deviations

pC polarimeters:

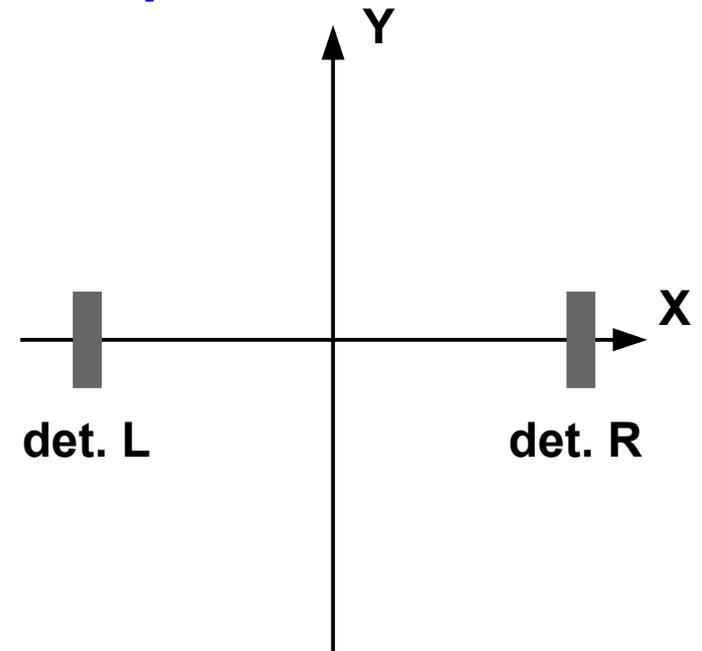
- Square root formula: use 2 (3) pairs detectors for H (V) targets
 - Have 2 (3) measures of lumi asymmetry for H (V) targets
 - For V targets have 2 measures of $\epsilon_Y \propto P_Y$
- Up/Down-stream polarims. (using ϵ vs. ϕ fit for $|\epsilon|$):
 - measurements \sim same time, 2 measures of $|\epsilon| \propto |P|$

Also today:

- Definitive measure non-vertical spin component P_x

Square root (cross ratio) formula

- Pair of detectors (L,R), 180° apart:
different detector acceptances a_L, a_R
- Exposed to up/down beam spins +,-:
different up/down luminosities L_+, L_-
- Beam polarization along Y-axis P_Y :
physics asymmetry $\epsilon = A_N P_Y$



- Measure 4 event counts:

$$\text{beam up: } N_{R+} = a_R L_+ (1+\epsilon) \quad N_{L+} = a_L L_+ (1-\epsilon)$$

$$\text{beam down: } N_{R-} = a_R L_- (1-\epsilon) \quad N_{L-} = a_L L_- (1+\epsilon)$$

- Extract 3 asymmetries (& stat. uncert.):

- physics asym. $\epsilon = A_N P_Y$

- luminosity asym. $\lambda \equiv (L_+ - L_-)/(L_+ + L_-)$; $(L_-/L_+) = (1-\lambda)/(1+\lambda)$

- acceptance asym. $\alpha \equiv (a_R - a_L)/(a_R + a_L)$

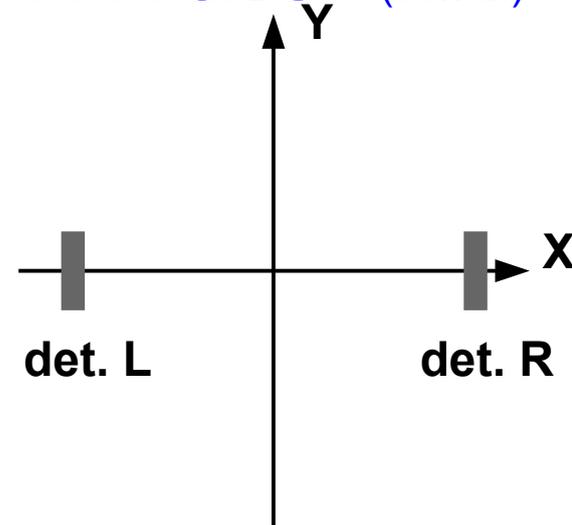
Square root (cross ratio) formula (contd.)

- 4 event counts: $N_{R+} = a_R L_+(1+\epsilon)$ $N_{L+} = a_L L_+(1-\epsilon)$
 $N_{R-} = a_R L_-(1-\epsilon)$ $N_{L-} = a_L L_-(1+\epsilon)$

- Cross ratio asymmetries:

$$\text{e.g. } \epsilon = (\sqrt{N_{R+} N_{L-}} - \sqrt{N_{L+} N_{R-}}) / (\sqrt{N_{R+} N_{L-}} + \sqrt{N_{L+} N_{R-}})$$

are exact under some assumptions about N_{R+} , N_{L+} etc.



Assumptions:

- Detector acceptances a_L, a_R are same for +/- beam spin states;
 - detector geometry $(\theta, \phi) \sim \text{fixed}$
 - +/- spin bunches separated by 100's nanoseconds; fair assumption
- Detectors are 180° apart; $\sim \text{fixed}$ by scattering chamber design
- +/- bunches same magnitude polarization: $|P_+| = |P_-|$
 - to 1st order: $\epsilon = \frac{1}{2}(|P_+| + |P_-|) A_N$ (mean of P magnitudes)
- Detectors have same analyzing power A_N
 - varying calibrations, target \Rightarrow varying E_{carbon} ranges \Rightarrow varying A_N
 - to 1st order: $\epsilon = \frac{1}{2}(A_{NR} + A_{NL})P$ (mean of detector A_N 's)
 - luminosity asym. λ unchanged to 1st order
 - **least certain assumption, test $A_N \propto \epsilon$ with cross checks**

pC polarim.: 3 detector pairs

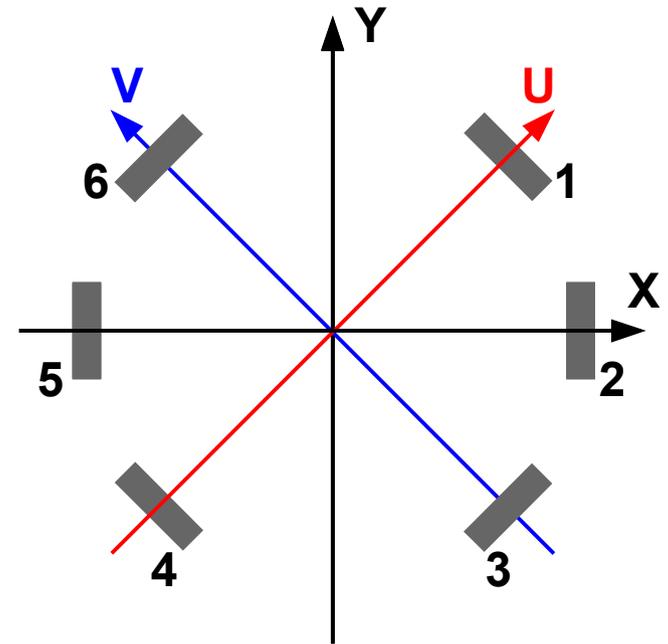
- 3 180° detector pairs, det. 1+4, 2+5, 3+6:

- Measure 3 sets of asymmetries:

$$\epsilon_{25} = A_N P_Y, \lambda_{25}, \alpha_{25}$$

$$\epsilon_{14} = A_N P_V, \lambda_{14}, \alpha_{14}$$

$$\epsilon_{36} = A_N P_U, \lambda_{36}, \alpha_{36}$$



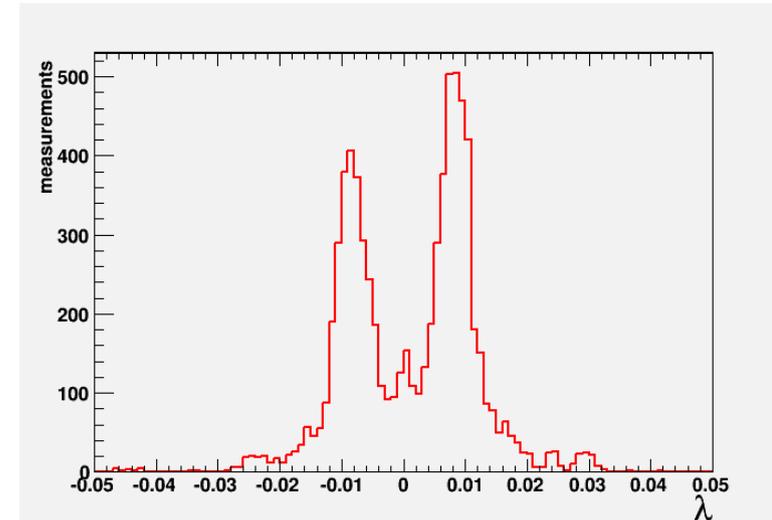
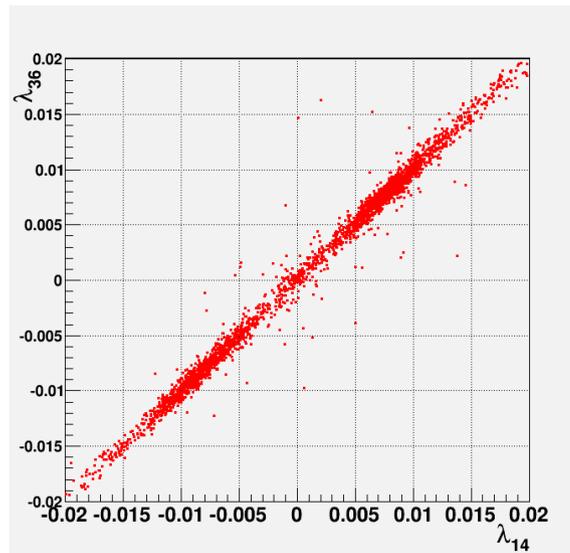
Cross checks:

- All detector pairs measure same beam, lumi asym. λ
compare $\lambda_{14}, \lambda_{25}, \lambda_{36}$: agree within stat. uncert. (↘ next slide)
- All detector pairs measure same beam, polarization P
two measures of $\epsilon_Y = A_N P_Y$, using $P_Y = 1/\sqrt{2}(P_V + P_U)$
 - from 90° det. 2+5: $\epsilon_{Y90} = \epsilon_{25}$ (vertical targets only)
 - from 45° det. 1+4, 3+6: $\epsilon_{Y45} = 1/\sqrt{2}(\epsilon_{14} + \epsilon_{36})$
 - compare $\epsilon_{Y90}, \epsilon_{Y45}$, check if A_N same all detectors (↘ next-next slide)

Luminosity asymmetries λ

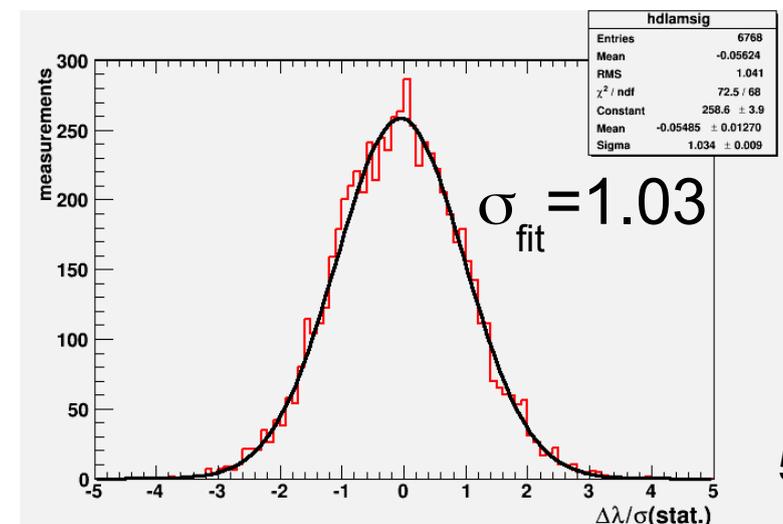
- Lumi asyms. $\lambda \sim \pm 1\%$
typically 111 bunches,
one extra \pm bunch

- λ from different detector
pairs track each other,
here e.g. λ_{36} vs. λ_{14} :



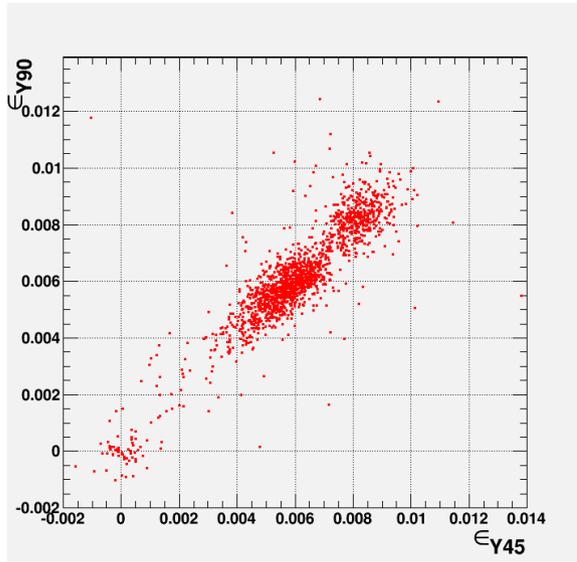
- Plot $(\lambda_A - \lambda_B)/\sigma(\text{stat})$
- Unit gaussian: no significant systematic,
square root formula works
- Good measure of λ for experiments?

↘ extra slide: λ from WCM bunch
currents not as good

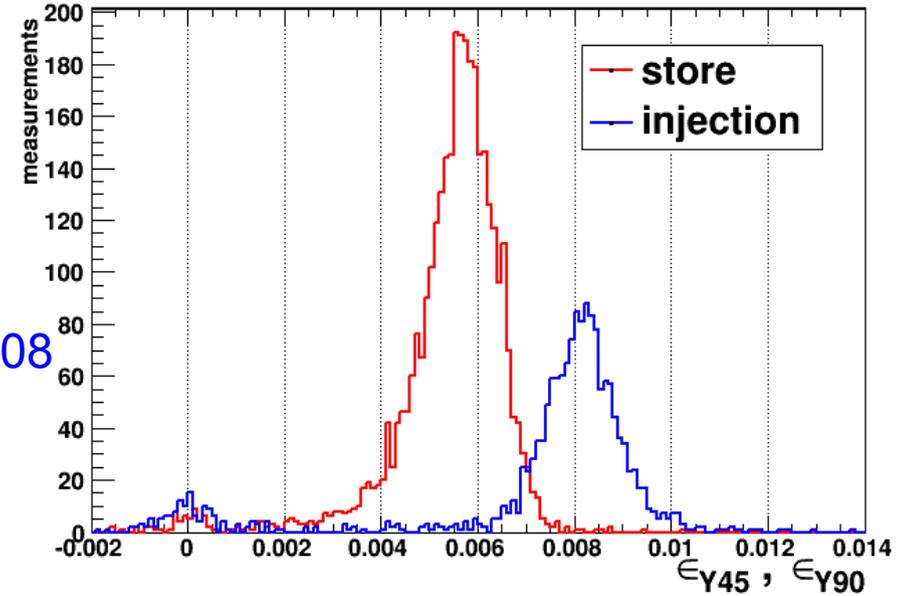


ϵ_Y from 90° , 45° detectors

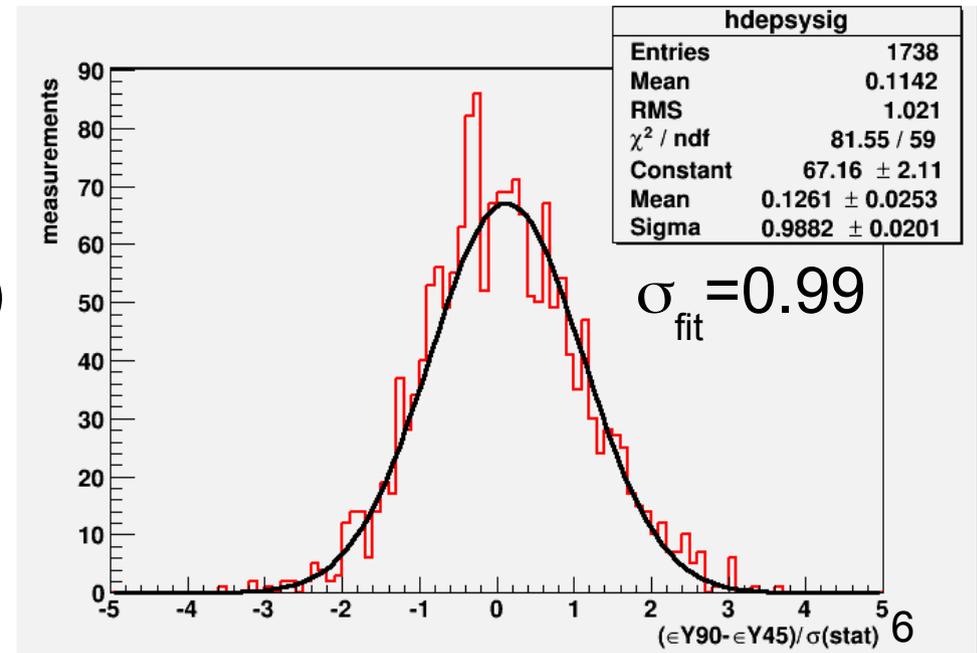
- Independently measure ϵ_Y with $90^\circ, 45^\circ$ detectors (vertical targets only):
- ϵ_{Y90} , ϵ_{Y45} nicely correlated:



store $\epsilon_Y \sim 0.006$
injection $\epsilon_Y \sim 0.008$

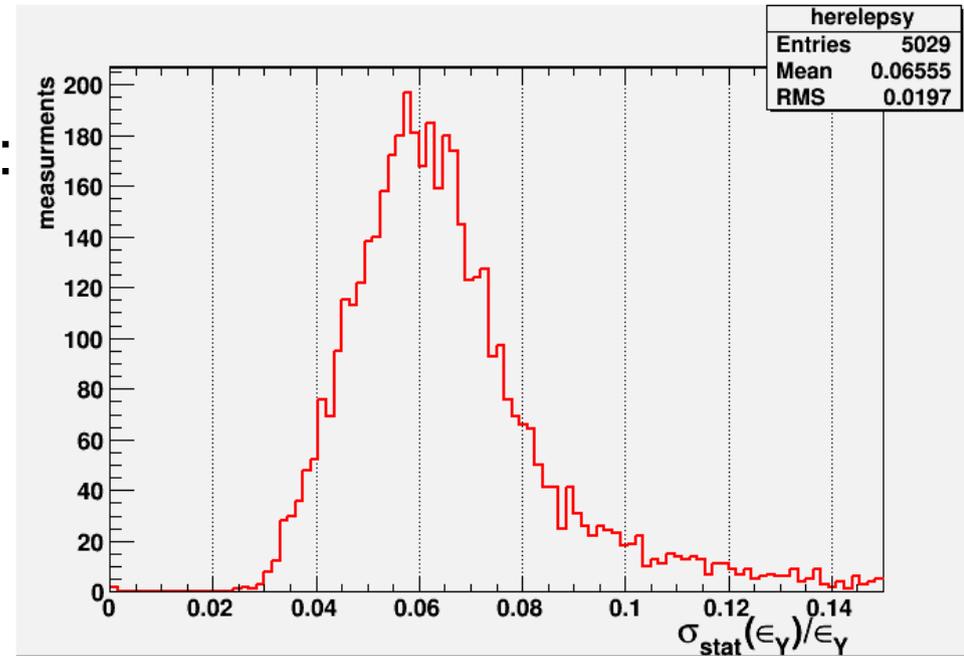


- Distribution $(\epsilon_{Y90} - \epsilon_{Y45}) / \sigma(\text{stat})$,
unit gaussian:
- $\sigma_{\text{fit}} = (1 \oplus \sigma_{\text{syst}} / \sigma_{\text{stat}})$, $\sigma_{\text{syst}}(\epsilon_Y) \ll \sigma_{\text{stat}}(\epsilon_Y)$
- The variations we see in ϵ_{Y90} , ϵ_{Y45}
are statistical, no indication
systematic variations



ϵ_Y from 90° , 45° detectors

- $\sigma_{\text{syst}}(\epsilon_Y) \ll \sigma_{\text{stat}}(\epsilon_Y)$
- Relative stat. uncert. $\sigma_{\text{stat}}(\epsilon_Y)/\epsilon_Y \approx 7\%$:
- So $\sigma_{\text{syst}}(\epsilon_Y)/\epsilon_Y \ll 7\%$,
say $\sigma_{\text{syst}}(\epsilon_Y)/\epsilon_Y \leq 1-2\%$
- $A_N \propto \epsilon_Y$
- So $\sigma_{\text{syst}}(A_N)/A_N \leq 1-2\%$



- **Systematic variations of A_N ,**
between detectors in the same polarimeter,
are below the 1-2% level

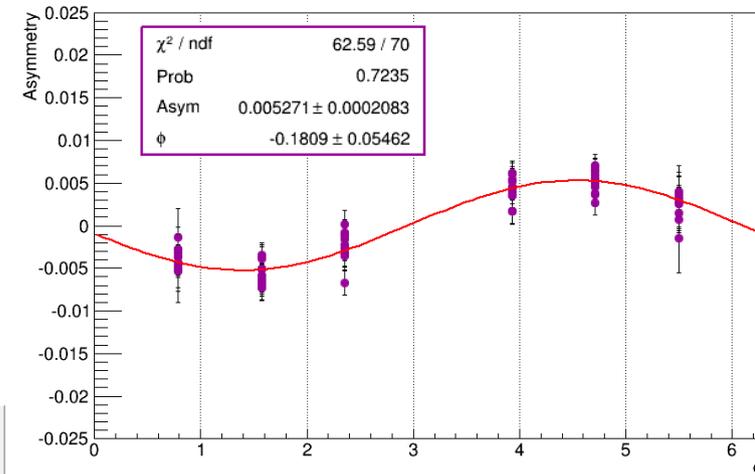
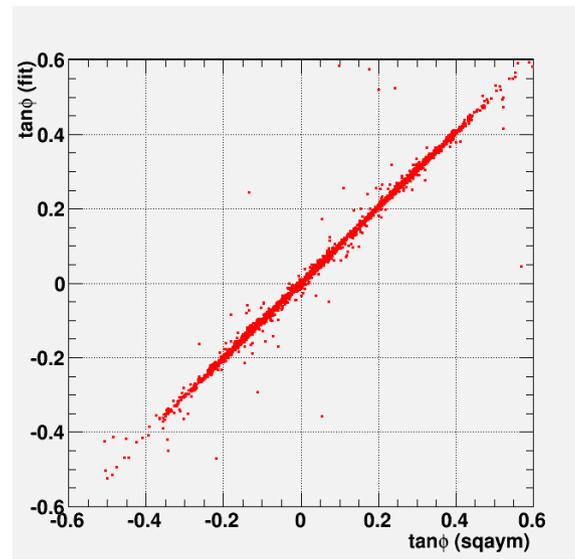
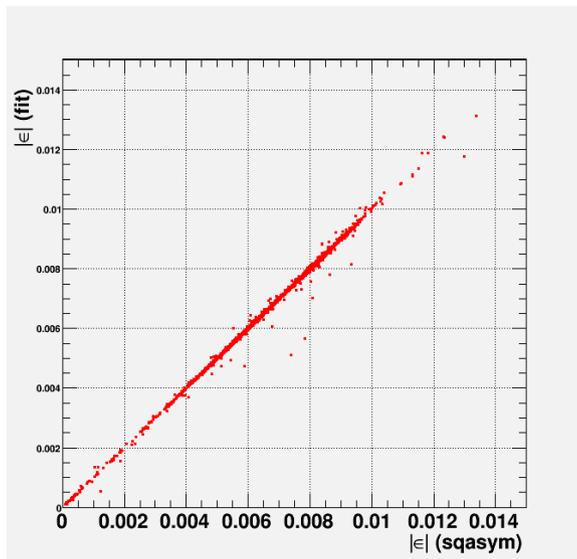
Same conclusion for:

(↘ plots extra slide)

- Each polarimeter (B1, Y1, B2, Y2)
- Injection/store
- α -gain not corrected for drifts (!?)

slight aside: Cross ratio vs. fit asymmetries

- Our default asymmetry (may be) from this fit: per-strip asymmetries using flawed approximation for relative luminosities
- It agrees well with rigorous $\sqrt{\epsilon}$ asymmetries, here e.g. $|\epsilon|$ and $\tan\phi = \epsilon_X/\epsilon_Y$:



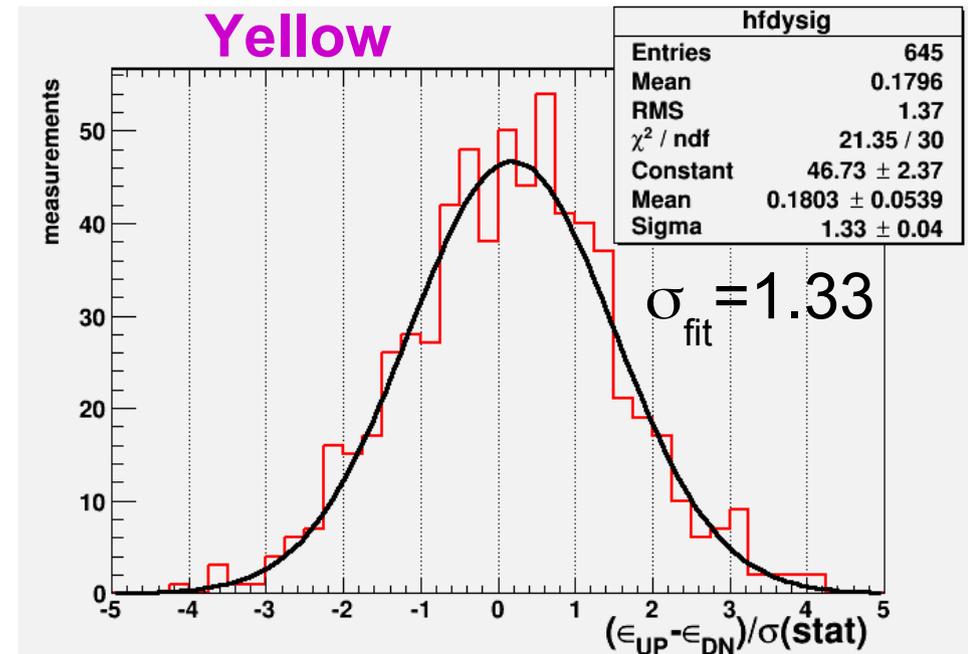
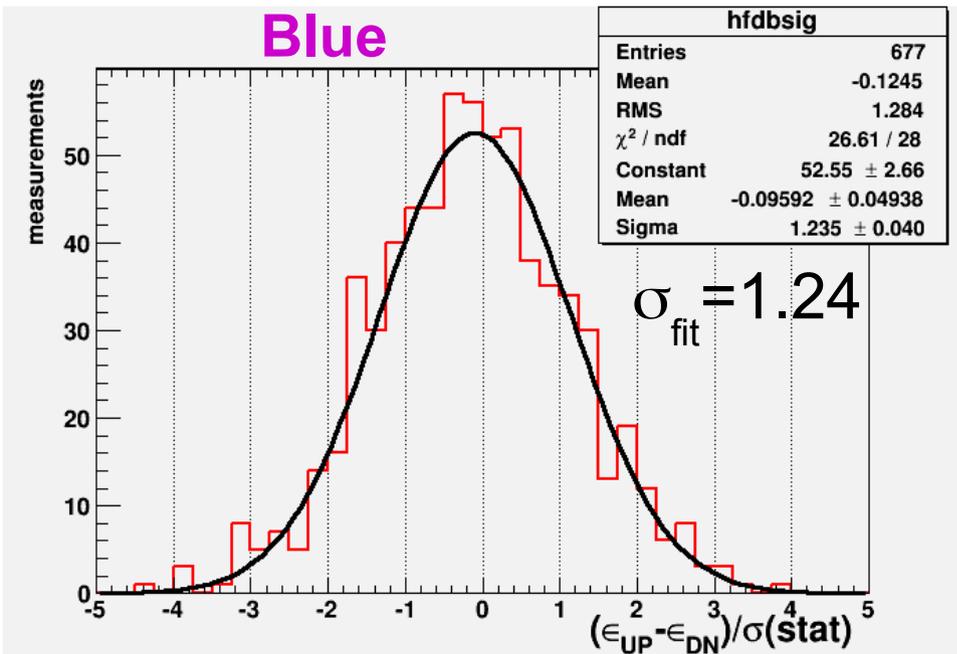
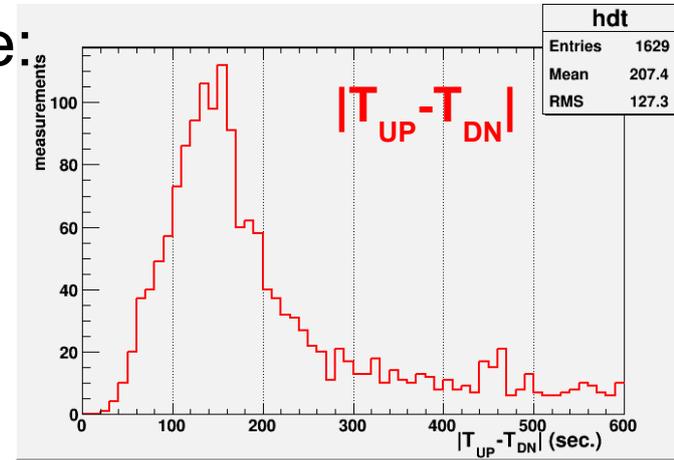
- Also: fit gives \sim same stat. uncert. as $\sqrt{\epsilon}$ asym. deviations (fit - $\sqrt{\epsilon}$ asym.) small compared to stat. uncert.
- **Conclusion: fit is adequate, small systematic effects**
use for further analysis (convenience, we're stuck with it)

$|\epsilon|$ from U/D polarimeters

- Select Blu or Yel U,D measurements ~same time:
 - typically within 3-4 minutes, select <10 min.
 - beam $|P|$ negligible drop in this time

- Compare U/D differences to stat. uncert.

$$(|\epsilon_{UP}| - |\epsilon_{DN}|) / \sigma(\text{stat}):$$



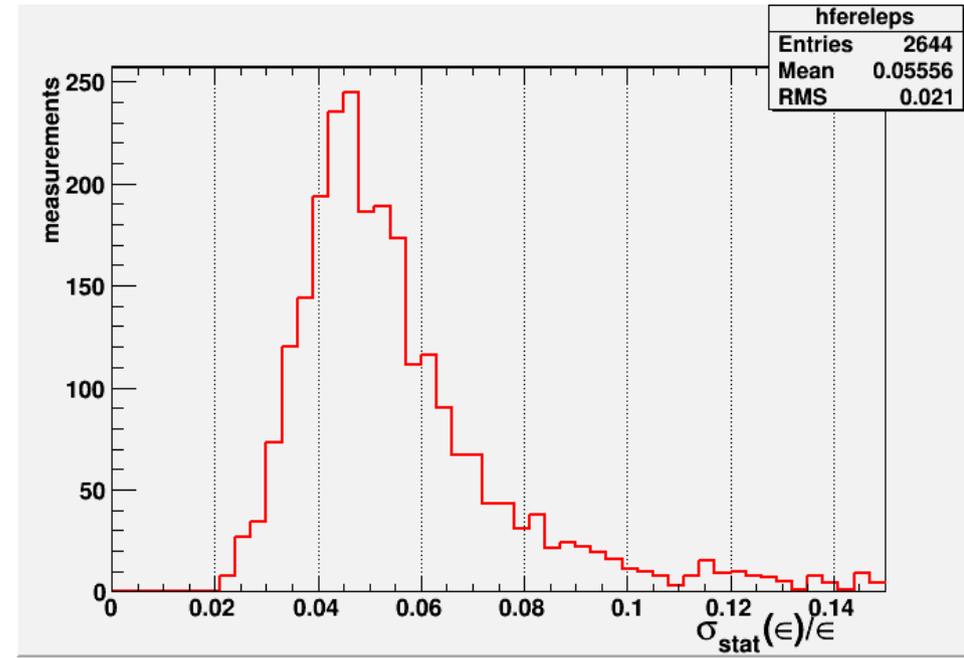
- Distributions significantly wider than unit gaussian: $\sigma_{\text{fit}} \sim 1.3$

- $\sigma_{\text{fit}} = (1 \oplus \sigma_{\text{syst}} / \sigma_{\text{stat}})$, $\sigma_{\text{syst}}(|\epsilon|)$ comparable to $\sigma_{\text{stat}}(|\epsilon|)$

$$\sigma_{\text{syst}}(|\epsilon|) \sim 0.83 \cdot \sigma_{\text{stat}}(|\epsilon|) \quad 9$$

$|\epsilon|$ from U/D polarimeters

- $\sigma_{\text{syst}}(\epsilon) \sim 0.83 \cdot \sigma_{\text{stat}}(\epsilon)$
- Relative stat. uncert. $\sigma_{\text{stat}}(\epsilon)/\epsilon \approx 6\%$:
- So $\sigma_{\text{syst}}(\epsilon)/\epsilon \approx 5\%$,
- $A_N \propto \epsilon$
- So $\sigma_{\text{syst}}(A_N)/A_N \approx 5\%$



- **Systematic variations of A_N ,**
between different polarimeters,
is about 5%

Same conclusion for:

(↘ plots extra slide)

- ϵ for U/D polarims. from cross asym. 45° det. instead of fit
(less statistics since 90° det. not used, less significant conclusion)

Summary ϵ systematics

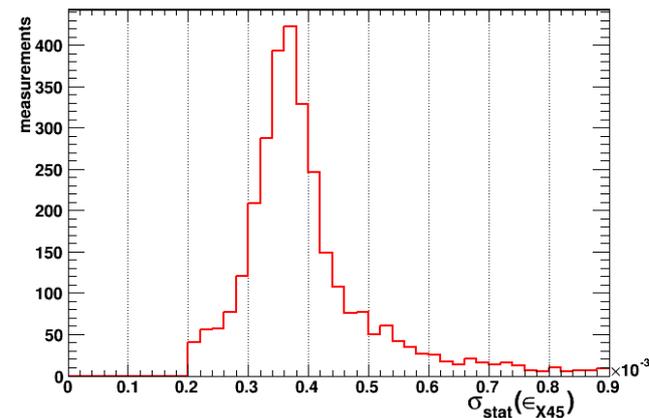
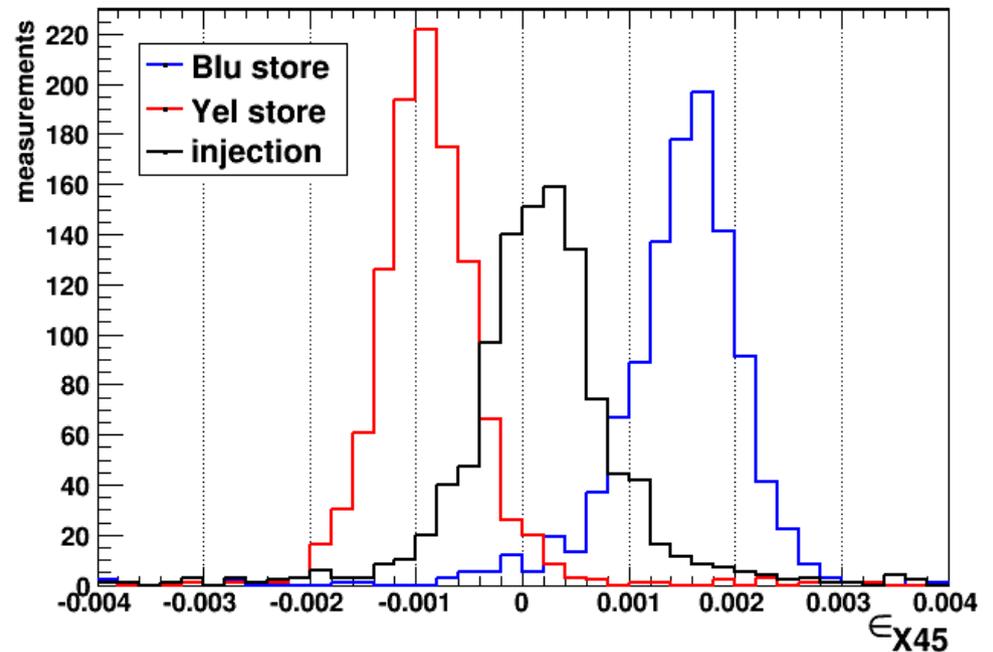
- Ascribe variations of ϵ as due to variations in A_N
e.g. variations in E_{carbon} range: miscalibration
dE/dx loss in targets
- Variations of ϵ in the *same polarimeter* are negligible:
 - miscalibrations different detectors insignificant
even when we ignore α -calibration drifts!
- Variations of ϵ between *different polarimeters* are $\sim 5\%$:
 - different polarimeters \rightarrow different targets
 \rightarrow different dE/dx loss in targets
 - expected magnitude effect on A_N 5-10%
(my slides polarim. mtg. 14.07.11)

Another lesson:

- Comparing systematic \leftrightarrow statistical fluctuations,
barely sensitive to systematics
- Increased statistics would enable real systematic studies

ϵ_X from 45° detectors

- 45° detectors: $1/\sqrt{2}(\epsilon_{14} - \epsilon_{36}) = \epsilon_X \propto P_X$
horizontal component spin vector
- Very clear:
@ injection $\epsilon_X \sim 0$
@ store $\epsilon_X > 0$ (Blu), $\epsilon_X < 0$ (Yel)
- In geographical coordinates:
at store both Blu and Yel spin vectors *tilted toward RHIC ring center*
- Widths ϵ_X distributions $\sim \epsilon_X$ stat. uncert.:
(\searrow $\langle \rangle$ \bullet ~~id~~ extra slide)
- So spin tilt @ store \sim fixed number,
 $\epsilon_X/\epsilon_Y \Rightarrow$ angle from vertical: Blu $\sim +16^\circ$
Yel $\sim -9^\circ$



Spin vector tilt @ H-jet?

- Clearly measure spin tilt at pC polarimeters
(~100 from IP12)
- Is there a spin tilt at H-jet (at IP12)?

Implications:

- H-jet measures $\epsilon_Y \propto P_Y$ (only 90° horizontal detectors)
- In pC/H-jet normalization we assume
H-jet measures magnitude $|P|$
- Spin tilt at H-jet would give scale shift in $|P|$,
e.g. spin tilt $16^\circ \Rightarrow 4\%$ scale shift

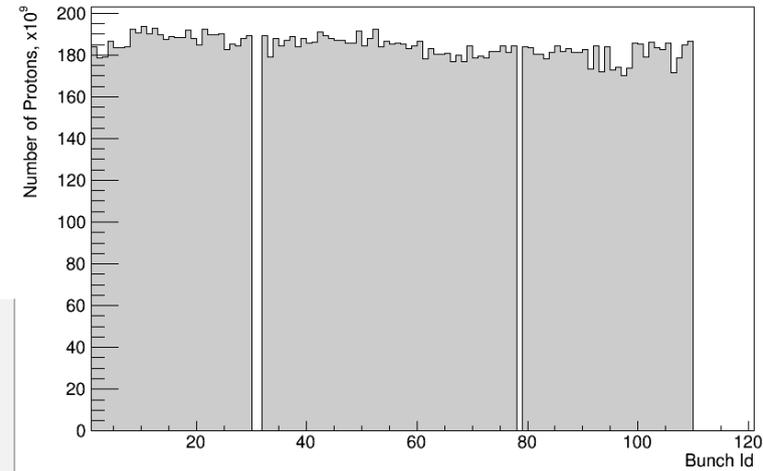
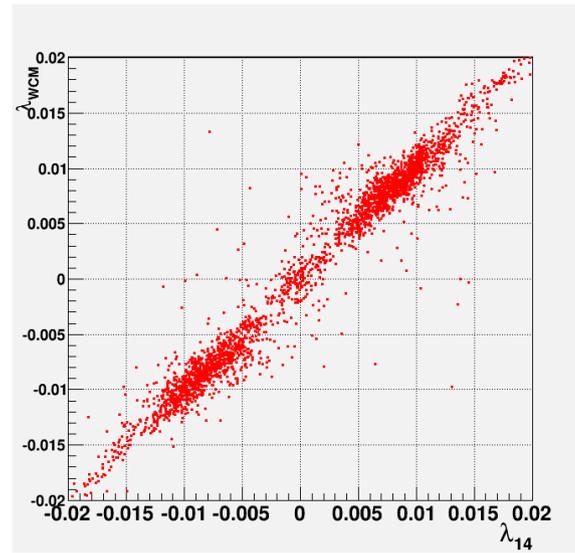
Should discuss with RHIC experts...

Extras

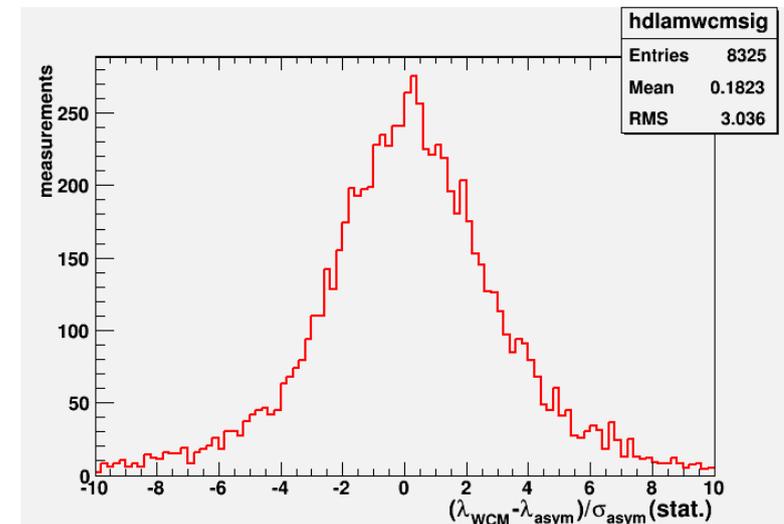
Luminosity asymmetry from WCM

- Bunch currents, sum I_+ , I_-
- measure $\lambda_{\text{WCM}} = (I_+ - I_-)/(I_+ + I_-)$

- λ_{WCM} correlates nicely with e.g. λ_{14} from det. 14 sqrt asym:

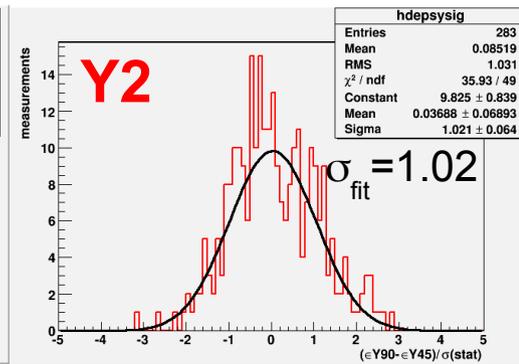
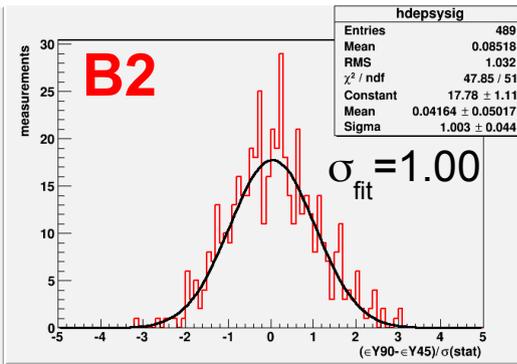
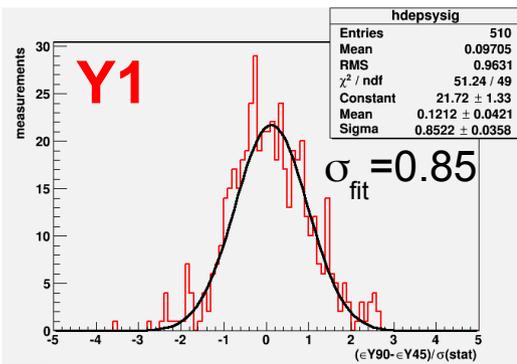
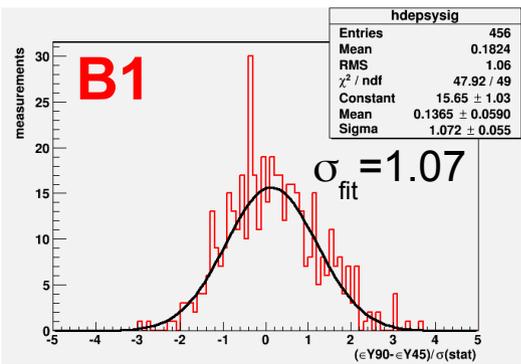


- Distribution $(\lambda_{\text{WCM}} - \lambda_{\text{asym}})/\sigma_{\text{asym}}$ (stat):
- RMS ~3: WCM uncertainties much larger than detector stat. uncert.

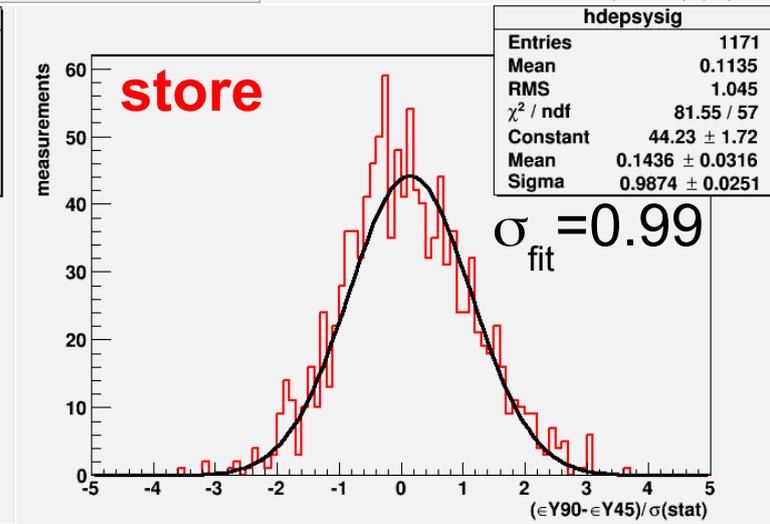
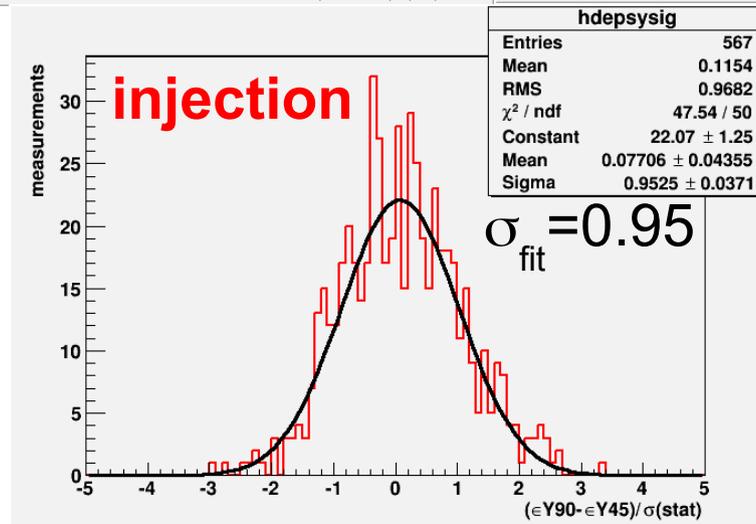


$(\epsilon Y90 - \epsilon Y45) / \sigma(\text{stat})$

- 4 polarimeters:

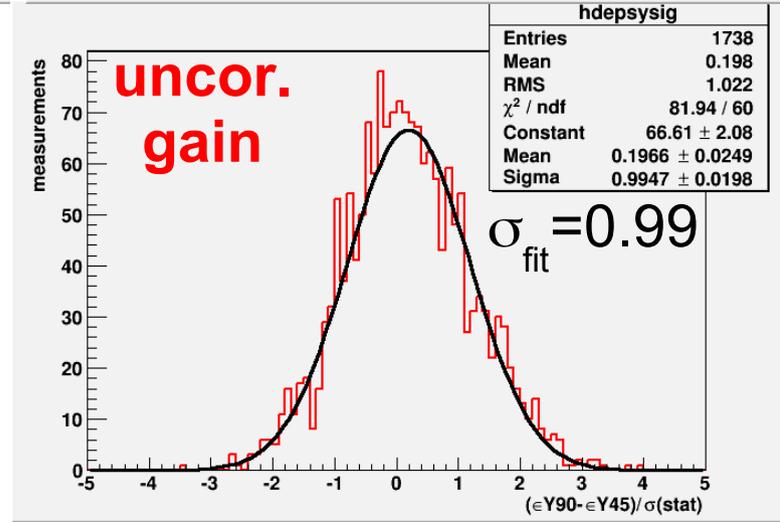


- injection / store:



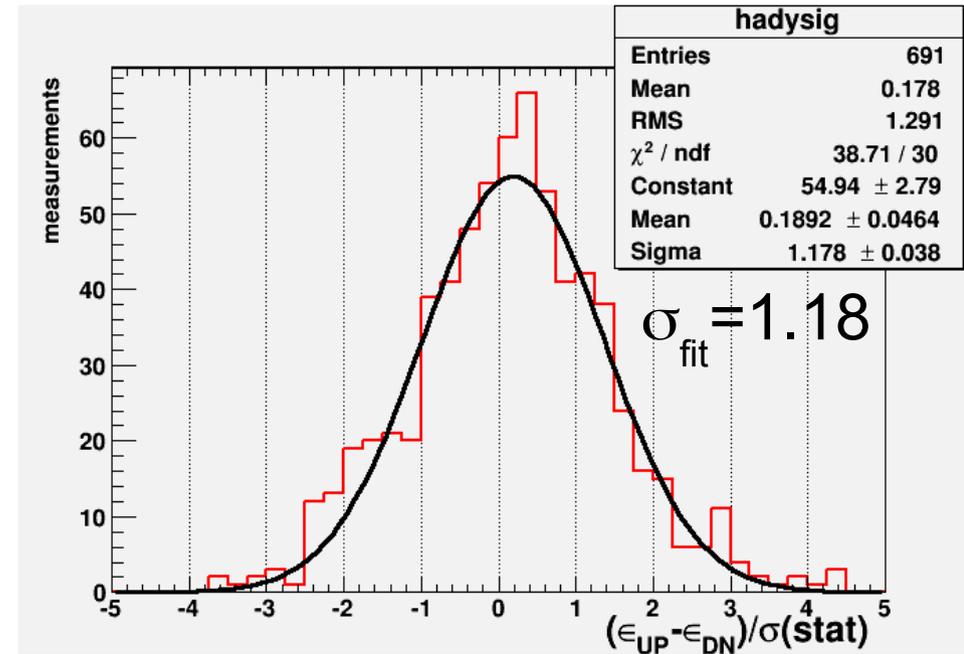
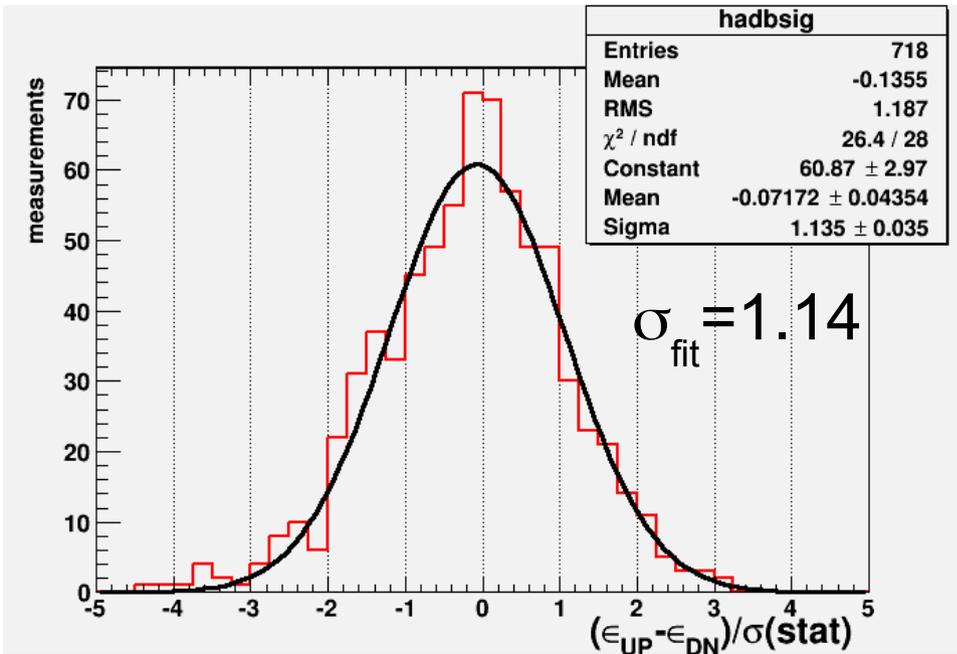
- α -gain not corrected:

- In all cases fluctuations
- consistent with statistics (RMS~1),
- no indication of systematic effects



$|\epsilon|$ from U/D: 45° det. asym.

- Select Blu or Yel U,D measurements ~same time:
- Instead of ϵ vs. ϕ fit get $|\epsilon|$ from 45° det. cross asym.
(easier to get. stat. uncert. from only 45° det.)
- Compare U/D differences to stat. uncert. ($|\epsilon_{UP}| - |\epsilon_{DN}|$)/ $\sigma(\text{stat})$:
(90° det. not used, less statistics, less significant conclusion)



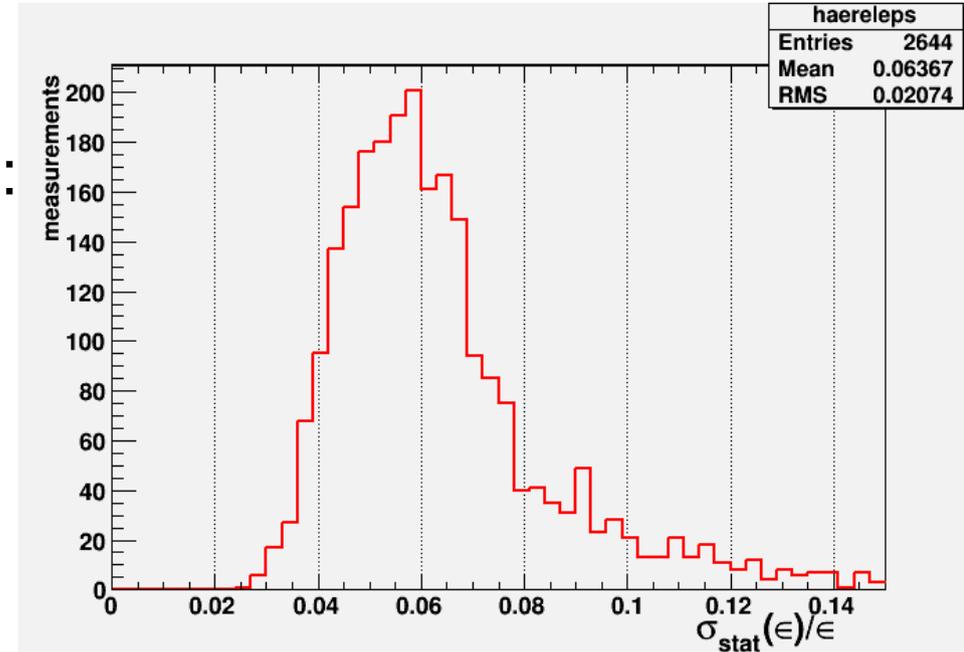
- Distributions significantly wider than unit gaussian: $\sigma_{\text{fit}} \sim 1.16$

- $\sigma_{\text{fit}} = (1 \oplus \sigma_{\text{syst}} / \sigma_{\text{stat}})$, $\sigma_{\text{syst}}(|\epsilon|)$ comparable to $\sigma_{\text{stat}}(|\epsilon|)$

$$\sigma_{\text{syst}}(\epsilon) \sim 0.59 \cdot \sigma_{\text{stat}}(\epsilon) \quad 17$$

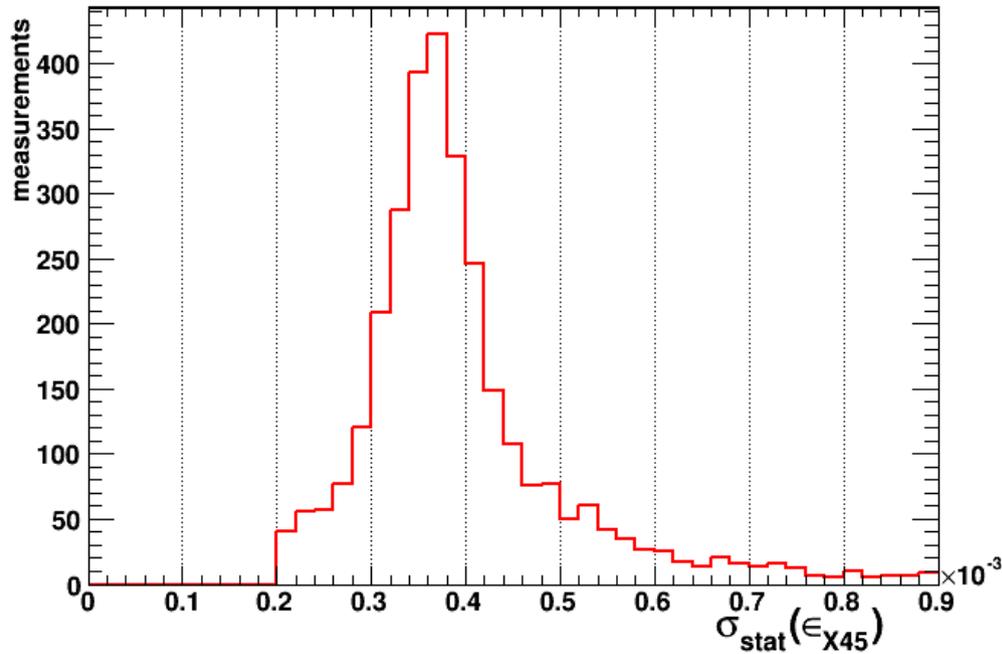
$|\epsilon|$ from U/D: 45° det. asym.

- $\sigma_{\text{syst}}(\epsilon_Y) \sim 0.59 \cdot \sigma_{\text{stat}}(\epsilon_Y)$
- Relative stat. uncert. $\sigma_{\text{stat}}(\epsilon)/\epsilon \approx 6.4\%$:
- So $\sigma_{\text{syst}}(\epsilon)/\epsilon \approx 4\%$,
- $A_N \propto \epsilon$
- So $\sigma_{\text{syst}}(A_N)/A_N \approx 4\%$



- **Systematic variations of A_N ,**
between different polarimeters,
is about 4%

RMS ϵ_X



- Widths of ϵ_X distributions $4-5 \times 10^{-4}$
- Stat. uncert. $\sim 4 \times 10^{-4}$
- Widths of ϵ_X distributions dominated by stat. fluctuations

